Amendments to the Abstract

Please replace the Abstract on page 10 of the application with the following paragraph.

A method of fabricating a photomask <u>includes transferring a is disclosed</u>. The method facilitates accurate measurement of the photomask critical dimension, without requiring the removal of the pellicle. A first pattern is transferred on <u>onto</u> a substrate in a first area, and <u>transferring</u> at least one test pattern is transferred on <u>onto</u> the substrate outside of the first area. A pellicle is attached to the substrate, <u>wherein</u> and the pellicle covers the first area, but does not cover the at least one test pattern.